

500.43281X00

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicants: MAKUUCHI et al  
Application No.: 10/714,943  
Filed: November 18, 2003  
For: SEMICONDUCTOR DEVICE AND TESTING METHOD OF  
SEMICONDUCTOR DEVICE  
Art Unit: 2629  
Examiner: L. SHAPIRO **CONF. No. 3730**

**AMENDMENT AFTER FINAL**

**MS: AMENDMENTS AF**  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

August 17, 2007

Sir:

In accordance with the provisions of 37 CFR §1.116, entry of the following Amendment is respectfully requested, noting the timely filing of a Petition for Extension of Time and a Notice of Appeal in this matter on July 2, 2007; please amend the above-identified application as listed below and as set forth on the following pages:

**Amendments to the Claims;**

**Remarks are included following the amendments.**